

Search Notes

Application/Control No.

10/804,174

Examiner

John D. Lee

Applicant(s)/Patent under
Reexamination

OKUNO ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
359	326,332	4/27/2006	JDL
385	122	4/27/2006	JDL
(All	Updated)		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Previous USPTO "WEST" Database search updated (same search terms)	4/27/2006	JDL